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## Solar Cells Reporting Summary

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## ü Experimental design

1.	Dimensions		
	Area of the tested solar cells	Yes No	The test area can be found in the section of Device Characterization.
	Method used to determine the device area	Yes No	The method can be found in the section of Device Characterization.
2.	Current-voltage characterization		
	Current density-voltage (J-V) plots in both forward and backward direction	Yes No	The hysteresis is very low in our device, and there is very small difference for the forward and backward scan direction. So, we only put the J-V plots in backward direction.
	Voltage scan conditions For instance: scan direction, speed, dwell times	Yes  No	We test device using a common scan conditions with speed of 100mV/s,dwell time of 100ms, backward and forward direction. In this work, the hysteresis is low, and we test the device using same scan conditions. So, we do not place the scan conditions into the text.
	Test environment For instance: characterization temperature, in air or in glove box	Yes No	The test environment can be found in the section of Device Characterization.
	Protocol for preconditioning of the device before its characterization	Yes No	The protocol for preconditioning of the device can be found in the section of Device Characterization and Supplementary Figure 16.
	Stability of the J-V characteristic Verified with time evolution of the maximum power point or with the photocurrent at maximum power point; see <u>ref. 7</u> for details.	Yes No	The stability of the the J-V characteristic can be found in Supplementary Figure 16.
3.	Hysteresis or any other unusual behaviour		
	Description of the unusual behaviour observed during the characterization	Yes No	There are not unusual behaviour observed during the characterization. The device has low hysteresis and long stability.
	Related experimental data	Yes No	The related experimental data can be found in Figure 4, Figure 5 and Supplementary Figure 16.
1.	Efficiency		
	External quantum efficiency (EQE) or incident photons to current efficiency (IPCE)	Yes No	The IPCE can be found in Figure 4 and Supplementary Figure 15.
	A comparison between the integrated response under the standard reference spectrum and the response measure under the simulator	Yes No	The comparison can be found in Figure 4 and the section of Prenucleation-enabled Efficient PVSC with High Consistency.
	For tandem solar cells, the bias illumination and bias voltage used for each subcell	Yes No	This work does not contain the tandem solar cells.
5.	Calibration		
	Light source and reference cell or sensor used for the	Yes No	The calibration can be found in section of Device Characterization.

	Confirmation that the reference cell was calibrated and certified	Yes No	This information can be found in section of Device Characterization.
	Calculation of spectral mismatch between the reference cell and the devices under test	Yes  No	We use the certified standard silicon cell as a reference cell. Altough there are some spectral mismatches, the silicon cell absorbs wider spectrum than perovskite solar cell and has long stability, which can guarantee light intensity almost same under ever test.
6.	Mask/aperture		
	Size of the mask/aperture used during testing	Yes No	The size of the mask/aperture can be found in section of Device Characterization.
	Variation of the measured short-circuit current density with the mask/aperture area	Yes  No	In this work, we do not compare the variation of Jsc with the aperture area. The active area of our device is 0.15cm2, and the aperture area of mask is 0.1 cm2.
7.	Performance certification		
	Identity of the independent certification laboratory that confirmed the photovoltaic performance	Yes  No	In this work, we do not carry out a performance certification in independent certification laboratory.
	A copy of any certificate(s)  Provide in Supplementary Information	Yes  No	In this work, we do not carry out a performance certification in independent certification laboratory.
8.	Statistics		
	Number of solar cells tested	Yes No	The statistics number of solar cells can be found in Figure 4.
	Statistical analysis of the device performance	Yes No	The statistical analysis of the device performance can be found in Figure 4 and the section of Prenucleation-enabled Efficient PVSC with High Consistency
9.	Long-term stability analysis		
	Type of analysis, bias conditions and environmental conditions For instance: illumination type, temperature, atmosphere humidity, encapsulation method, preconditioning temperature	Yes No	Long-term stability analysis can be found in Supplementary Figure 16.